

### **Enabling cross-layer reliability and functional safety assessment through ML-based compact models**

Alexandrescu, Dan; **Balakrishnan, Aneesh**; Lange, Thomas; Glorieux, Maximilien Proceedings : 2020 26th IEEE International Symposium on On-Line Testing and Robust System Design : IOLTS 2020, Napoli, Italy, July 13-16, 2020 : virtual edition 2020 / 6 p. : ill <https://doi.org/10.1109/IOLTS50870.2020.9159750>

### **High-level test data generation for software based self-test in microprocessors**

**Oyeniran, Adeboye Stephen; Jasnetski, Artjom; Tšertov, Anton; Ubar, Raimund-Johannes** 2017 6th Mediterranean Conference on Embedded Computing (MECO) : including ECYPS'2017 : proceedings : research monograph : Bar, Montenegro, June 11th-15th, 2017 2017 / p. 86-91 : ill <https://doi.org/10.1109/MECO.2017.7977167>

### **Teaching digital system test**

**Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Kruus, Margus** The 27th EAEEIE Annual Conference : June 7-9, 2017, Grenoble 2017 / [6] p